## Notice of References Cited Application/Control No. | Applicant(s)/Patent Under Reexamination AHN ET AL. | Examiner | Art Unit | Page 1 of 1

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-2003/0053403	03-2003	Miyamoto et al.	369/275.3
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	D	US-			
	E	US-			
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## **NON-PATENT DOCUMENTS**

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